

# Search Notes



Application/Control No.

10/522,337

Examiner

Tran N. Nguyen

Applicant(s)/Patent under  
Reexamination

KAYAMA ET AL.

Art Unit

2834

## SEARCHED

Class	Subclass	Date	Examiner
310	81 254	5/24/06	[Signature]
340	407.1 7.3		
	7.6		

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR